



	Experiment title: Investigation of the temperature dependent structural phase transition in $(\text{CuGaS}_2)_{1-x}(\text{CuGaSe}_2)_x$ alloys	Experiment number: HS-3167
Beamline:	Date of experiment: from: 01-Nov-2006 to: 07-Nov-2006	Date of report: 15-09-2007
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Report:

In recent years growing interest has been paid to the I-III-VI₂ complex semiconductor compounds (I-Cu, Ag; III-Al, Ga, In and VI-S, Se, Te). These compounds belong to the chalcopyrite family and crystallize in the chalcopyrite type structure (space group $I\bar{4}2d$). They are considered to be possible candidates for application in solar power as absorber material in thin film solar cells, optoelectronics and devices for the transferring and processing of information [1-3].

Obtaining the solid solutions between the compounds of the I-III-VI₂ group, for example CuGaS₂ and CuGaSe₂, gives the opportunity to vary the physical properties systematically. For example, the optical band gap in CuGaS_{2-x}Se_x mixed crystals varies between 2.43 eV (CuGaS₂) and 1.68 eV (CuGaSe₂) [4].

Earlier in-situ high temperature diffraction experiments with Synchrotron X-rays have shown for the first time the occurrence of a structural phase transition from the chalcopyrite type structure [chp] to the sphalerite type structure [sph] in CuGaSe₂ at ~ 1040°C [5]. On the other hand, no phase transition exists in CuGaS₂ before the melting of the compound at 1240°C [6,7].

The aim of the current experiment was to verify these results and to obtain the temperature dependent structural phase transition in the CuGaS_{2-x}Se_x mixed crystals. Of special interest was the critical composition at which the phase transition vanishes.

The CuGaS_{2-x}Se_x powder samples were prepared by solid state reaction from the pure elements in sealed evacuated silica tubes. The chemical composition was determined by electron microprobe measurements.

Powder diffraction experiments were performed at the high energy beamline ID15 in a temperature range from 300°C to 1100°C using a furnace for 2-D diffraction and the MAR345 image plate detector. A high energy monochromatic beam (energy of 88.95 keV) was used which gives the advantage of high penetration. The samples were encapsulated in evacuated silica ampoules (4mm diameter) to avoid e. g. sulfur and/or selenium evaporation during heating. The data collection was done during heating the sample, first with a rate of 300K/h and at higher temperatures with a rate of 38K/h. The latter realises recording an image every centigrade degree (10sec measurement + readout the 2-D detector). An Aluminum reference sample was used to calibrate the beam energy ($\lambda = 0.1403676 \text{ \AA}$) and the sample-detector distance. The 1D diffractograms were obtained by radial integration of the images.

After visual inspection of the 2D-diffractograms, the temperatures at which the structural phase transition [chp] → [sph] occurs can be pointed out. Table 1 resumes these temperatures during the heating cycle. The results of the

experiment revealed, that the the structural phase transition [chp] → [sph] in $\text{CuGaS}_{2-x}\text{Se}_x$ mixed crystals vanishes for $x < 0.7$ (see figure 1).

Table 1: Temperatures of decomposition, phase transition and melting of $\text{CuGaS}_{2-x}\text{Se}_x$ mixed crystals.
(* - no measurements in this temperature region because of synchrotron beam stability problems)

CuGaSe ₂ in CuGaS ₂ [Mol%]	sample composition	decomposition temperature range [°C]	transition temperature [°C]	melting temperature [°C]
100	CuGaSe ₂	1032 – 1042	1048	1105
80	Cu _{1.006} Ga _{0.994} Se _{1.588} S _{0.412}	1057 – 1066	1085	*
70	Cu _{1.008} Ga _{0.992} Se _{1.323} S _{0.677}	*	1096	*
60	Cu _{0.991} Ga _{1.009} Se _{1.246} S _{0.754}	1126 – 1127	-	1129
50	Cu _{1.002} Ga _{1.006} Se _{0.962} S _{1.038}	1143 – 1152	-	1154
20	Cu _{1.006} Ga _{0.988} Se _{0.463} S _{1.537}	1193 – 1198	-	1200
0	CuGaS ₂	1220 – 1239	-	1240

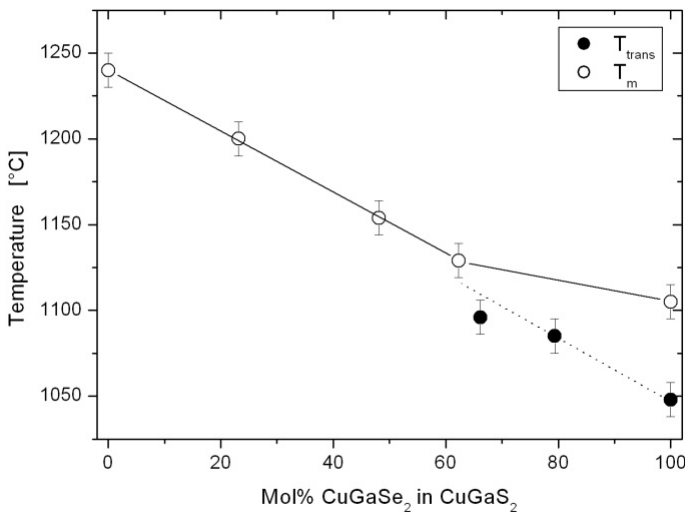


Figure 1: Melting temperature (T_m) and temperature of the phase transition (T_{trans}) of $\text{CuGaS}_{2-x}\text{Se}_x$ mixed crystals

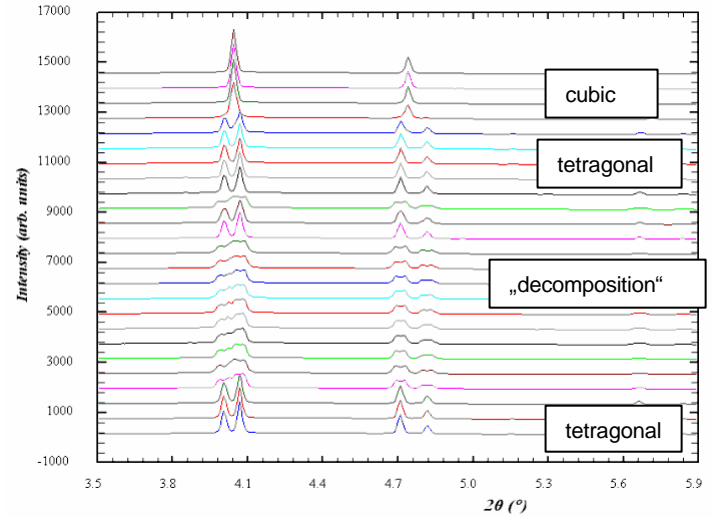


Figure 2: Part of the diffractograms of the $\text{Cu}_{1.006}\text{Ga}_{0.994}\text{Se}_{1.588}\text{S}_{0.412}$ mixed crystal in the temperature range 1054°C (down) to 1088°C (top).

Beside the structural phase transition another interesting feature was obtained from the measurements. Before the transition temperature is reached, the diffraction pattern changes drastically indicating a decomposition-like behaviour of the compound (see figure 2). The same specific characteristic was also observed in the former experiments [5]. Thus it is obvious, that this is not an artefact of the experiment. The current study has revealed, that this feature not only occurs in CuGaSe_2 , but also in the $\text{CuGaS}_{2-x}\text{Se}_x$ mixed crystals (see table 1). Moreover it was shown, that with increasing sulfur content the decomposition temperature range is decreasing (with the exception of CuGaS_2).

The least-square structure refinements, Rietveld type, were started to carry out in the most interesting 1D diffractograms at different temperatures.

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